

Liang Zhang

List of Publications by Year in descending order

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84
papers

2,808
citations

159585

30
h-index

189892

50
g-index

86
all docs

86
docs citations

86
times ranked

1067
citing authors

#	ARTICLE	IF	CITATIONS
1	Microstructure and properties of Sn-Ag and Sn-Sb lead-free solders in electronics packaging: a review. <i>Journal of Materials Science: Materials in Electronics</i> , 2022, 33, 2259-2292.	2.2	9
2	Interfacial reaction and properties of Sn _{0.3} Ag _{0.7} Cu containing nano-TiN solder joints. <i>Journal of Materials Science: Materials in Electronics</i> , 2022, 33, 3320-3330.	2.2	7
3	Structure and Properties of Au-Sn Lead-Free Solders in Electronic Packaging. <i>Materials Transactions</i> , 2022, 63, 93-104.	1.2	5
4	Development of lead-free interconnection materials in electronic industry during the past decades: Structure and properties. <i>Materials and Design</i> , 2022, 215, 110439.	7.0	27
5	Influence of SiC nanowires on the microstructures and properties of Ag-Cu-Ti filler metals and brazed joints. <i>International Journal of Modern Physics B</i> , 2022, 36, .	2.0	0
6	Influence of copper nanowires on properties and microstructure of low-Ag Sn-1Ag-0.5Cu solders. <i>Journal of Materials Science: Materials in Electronics</i> , 2022, 33, 7923-7932.	2.2	7
7	Enhancement of structure and properties of Sn58Bi solder by AlN ceramic particles. <i>Journal of Materials Research and Technology</i> , 2022, 19, 2584-2595.	5.8	23
8	Materials modification of the lead-free solders incorporated with micro/nano-sized particles: A review. <i>Materials and Design</i> , 2021, 197, 109224.	7.0	59
9	The analysis of the fracture mechanism of thermal simulation CGHAZ of AHSS DP780: based on response surface method and quantum genetic algorithm. <i>Welding in the World, Le Soudage Dans Le Monde</i> , 2021, 65, 563-572.	2.5	4
10	Effect of Ni ₃ Sn ₄ on the Thermo-Mechanical Fatigue Life of Solder Joints in 3D IC. <i>Frontiers in Materials</i> , 2021, 8, .	2.4	5
11	Reliability and strength of Cu-Sn _{0.5} CuZnAl-Cu TLP bonded joints during thermal cycling. <i>Journal of Materials Science: Materials in Electronics</i> , 2021, 32, 19264-19274.	2.2	5
12	Influences of silicon carbide nanowires TM addition on IMC growth behavior of pure Sn solder during solid-liquid diffusion. <i>Journal of Materials Science: Materials in Electronics</i> , 2021, 32, 18067-18075.	2.2	10
13	Filler metals, brazing processing and reliability for diamond tools brazing: A review. <i>Journal of Manufacturing Processes</i> , 2021, 66, 651-668.	5.9	48
14	Microstructure evolution of Cu/Sn58Bi/Cu solder joint bearing graphene nanosheets for 3D packaging. <i>Journal of Materials Science: Materials in Electronics</i> , 2021, 32, 16970-16978.	2.2	6
15	Recent advances on SnBi low-temperature solder for electronic interconnections. <i>Journal of Materials Science: Materials in Electronics</i> , 2021, 32, 22731-22759.	2.2	24
16	Effect of CNTs on the intermetallic compound growth between Sn solder and Cu substrate during aging and reflowing. <i>Journal of Materials Science: Materials in Electronics</i> , 2021, 32, 2655-2666.	2.2	13
17	Influence of doping Ti particles on intermetallic compounds growth at Sn58Bi/Cu interface during solid-liquid diffusion. <i>Journal of Materials Science: Materials in Electronics</i> , 2021, 32, 3341-3351.	2.2	6
18	Effects of SiC nanowires on reliability of Sn58Bi-0.05GNSs/Cu solder joints. <i>International Journal of Modern Physics B</i> , 2021, 35, 2150007.	2.0	10

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19	Interfacial reaction and properties of Sn/Cu solder reinforced with graphene nanosheets during solid-liquid diffusion and reflowing. <i>Journal of Materials Science: Materials in Electronics</i> , 2021, 32, 26666-26675.	2.2	4
20	Interfacial evolution of pure Sn solder bearing silicon carbide nanowires under isothermal aging and thermal cycling. <i>Journal of Materials Research and Technology</i> , 2021, 15, 3974-3982.	5.8	20
21	Effect of Thermal Cyclic Loading on Stress-Strain Response and Fatigue Life of 3D Chip Stacking Structure. <i>Chinese Journal of Mechanical Engineering (English Edition)</i> , 2021, 34, .	3.7	3
22	Recent progress in SLID bonding in novel 3D-IC technologies. <i>Journal of Alloys and Compounds</i> , 2020, 818, 152825.	5.5	71
23	Effect of addition of CuZnAl particle on the properties of Sn solder joint. <i>Journal of Materials Processing Technology</i> , 2020, 278, 116507.	6.3	19
24	Inhibition of intermetallic compounds growth at Sn-58Bi/Cu interface bearing CuZnAl memory particles (2-6 μ m). <i>Journal of Materials Science: Materials in Electronics</i> , 2020, 31, 2466-2480.	2.2	57
25	Properties and microstructure evolution of Sn-Cu-Ni/Cu joints bearing carbon nanotubes and graphene nanosheets for solar cell. <i>Journal of Materials Science: Materials in Electronics</i> , 2020, 31, 21758-21766.	2.2	6
26	Review of microstructure and properties of low temperature lead-free solder in electronic packaging. <i>Science and Technology of Advanced Materials</i> , 2020, 21, 689-711.	6.1	36
27	Microstructures, interface reaction, and properties of Sn-Ag-Cu and Sn-Ag-Cu-0.5CuZnAl solders on Fe substrate. <i>Journal of Materials Science: Materials in Electronics</i> , 2020, 31, 6645-6653.	2.2	20
28	Effects of nanoparticles on properties and interface reaction of Sn solder for microelectronic packaging. <i>International Journal of Modern Physics B</i> , 2020, 34, 2050064.	2.0	7
29	The Influence of Carbon Nanotubes on the Properties of Sn Solder. <i>Materials Transactions</i> , 2020, 61, 718-722.	1.2	6
30	Microstructures and properties of SnAgCu lead-free solders bearing CuZnAl particles. <i>Journal of Materials Science: Materials in Electronics</i> , 2019, 30, 15054-15063.	2.2	15
31	Research status on surface metallization of diamond. <i>Materials Research Express</i> , 2019, 6, 122005.	1.6	7
32	Numerical simulation and welding parameters optimization for minimum deformation of AHSS based on RSM & QGA. <i>Materials Research Express</i> , 2019, 6, 1165e9.	1.6	3
33	Reliability issues of lead-free solder joints in electronic devices. <i>Science and Technology of Advanced Materials</i> , 2019, 20, 876-901.	6.1	104
34	Influences of doping Ti nanoparticles on microstructure and properties of Sn58Bi solder. <i>Journal of Materials Science: Materials in Electronics</i> , 2019, 30, 17583-17590.	2.2	23
35	Wettability, interfacial reaction and mechanical properties of Sn/Sn-CuZnAl solder and Cu sheet during solid-liquid diffusion. <i>Journal of Materials Science: Materials in Electronics</i> , 2019, 30, 18462-18470.	2.2	4
36	Effect of CuZnAl particles addition on microstructure of Cu/Sn58Bi/Cu TLP bonding solder joints. <i>Vacuum</i> , 2019, 167, 301-306.	3.5	54

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37	Structure and properties of Sn-Cu lead-free solders in electronics packaging. <i>Science and Technology of Advanced Materials</i> , 2019, 20, 421-444.	6.1	83
38	Stress analysis and structural optimization of 3-D IC package based on the Taguchi method. <i>Soldering and Surface Mount Technology</i> , 2019, 32, 42-47.	1.5	22
39	Interface reaction and intermetallic compound growth behavior of Sn-Ag-Cu lead-free solder joints on different substrates in electronic packaging. <i>Journal of Materials Science</i> , 2019, 54, 1741-1768.	3.7	146
40	Effect of thermal cycles on interface and mechanical property of low-Ag Sn _{1.0} Ag _{0.5} Cu(nano-Al)/Cu solder joints. <i>Journal of Materials Science: Materials in Electronics</i> , 2018, 29, 9757-9763.	2.2	15
41	Materials, processing and reliability of low temperature bonding in 3D chip stacking. <i>Journal of Alloys and Compounds</i> , 2018, 750, 980-995.	5.5	72
42	Alkaline fermentation and elutriation of waste activated sludge for short chain fatty acids abstraction. <i>Journal of Chemical Technology and Biotechnology</i> , 2018, 93, 138-145.	3.2	0
43	FxTDO based non-singular terminal sliding mode control for second-order uncertain systems. <i>IET Control Theory and Applications</i> , 2018, 12, 2459-2467.	2.1	30
44	Achieve efficient nitrogen removal from real sewage in a plug-flow integrated fixed-film activated sludge (IFAS) reactor via partial nitrification/anammox pathway. <i>Bioresource Technology</i> , 2017, 239, 294-301.	9.6	73
45	Effects of CuZnAl Particles on Properties and Microstructure of Sn-58Bi Solder. <i>Materials</i> , 2017, 10, 558.	2.9	19
46	Cu ₆ Sn ₅ Whiskers Precipitated in Sn _{3.0} Ag _{0.5} Cu/Cu Interconnection in Concentrator Silicon Solar Cells Solder Layer. <i>Materials</i> , 2017, 10, 327.	2.9	10
47	Properties and Microstructures of Sn-Bi-X Lead-Free Solders. <i>Advances in Materials Science and Engineering</i> , 2016, 2016, 1-15.	1.8	24
48	Effect of Nd on whiskers growth behavior of SnAgCu solders in electronic packaging. <i>Journal of Materials Science: Materials in Electronics</i> , 2016, 27, 9584-9588.	2.2	1
49	Whisker growth on SnAgCu-xPr solders in electronic packaging. <i>Journal of Materials Science: Materials in Electronics</i> , 2016, 27, 5618-5621.	2.2	6
50	Effect of nano-Al addition on properties and microstructure of low-Ag content Sn _{1.0} Ag _{0.5} Cu solders. <i>Journal of Materials Science: Materials in Electronics</i> , 2016, 27, 7665-7673.	2.2	44
51	Properties and Microstructures of Sn-Ag-Cu-X Lead-Free Solder Joints in Electronic Packaging. <i>Advances in Materials Science and Engineering</i> , 2015, 2015, 1-16.	1.8	41
52	Reliability study of industry Sn _{3.0} Ag _{0.5} Cu/Cu lead-free soldered joints in electronic packaging. <i>Journal of Materials Science: Materials in Electronics</i> , 2015, 26, 9164-9170.	2.2	17
53	Wettability optimization analysis of lead-free solders with Taguchi method. <i>Journal of Materials Science: Materials in Electronics</i> , 2015, 26, 2605-2608.	2.2	3
54	Interfacial compounds growth of SnAgCu(nano La ₂ O ₃)/Cu solder joints based on experiments and FEM. <i>Journal of Alloys and Compounds</i> , 2015, 635, 55-60.	5.5	43

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55	Creep behavior of SnAgCu solders containing nano-Al particles. Journal of Materials Science: Materials in Electronics, 2015, 26, 3615-3620.	2.2	18
56	Determination of La/CeO ₂ content in ilmenite electrode coating. Rare Metals, 2015, 34, 505-509.	7.1	3
57	Sizes effect of CeSn ₃ on the whiskers growth of SnAgCuCe solder joints in electronic packaging. Journal of Materials Science: Materials in Electronics, 2015, 26, 6194-6197.	2.2	6
58	Microstructures and properties of Sn ₅₈ Bi, Sn ₃₅ Bi _{0.3} Ag, Sn ₃₅ Bi _{1.0} Ag solder and solder joints. Journal of Materials Science: Materials in Electronics, 2015, 26, 7629-7634.	2.2	38
59	Reliability of SnAgCu/SnAgCuCe solder joints with different heights for electronic packaging. Journal of Materials Science: Materials in Electronics, 2014, 25, 4489-4494.	2.2	8
60	Finite Element Analysis of SnAgCu(Zn, Co, Fe) Lead-free Solder Joints for Electronic Packaging. International Journal of Nonlinear Sciences and Numerical Simulation, 2014, 15, 197-206.	1.0	10
61	Reliability of Lead-free Solder Joints in WLCSP Device with Finite Element Simulation and Taguchi Method. International Journal of Nonlinear Sciences and Numerical Simulation, 2014, 15, 405-410.	1.0	10
62	Properties enhancement of SnAgCu solders containing rare earth Yb. Materials & Design, 2014, 57, 646-651.	5.1	44
63	Reliability of lead-free solder joints in CSP device under thermal cycling. Journal of Materials Science: Materials in Electronics, 2014, 25, 1209-1213.	2.2	48
64	Structure and properties of lead-free solders bearing micro and nano particles. Materials Science and Engineering Reports, 2014, 82, 1-32.	31.8	248
65	Properties and microstructures of SnAgCu-x Eu alloys for concentrator silicon solar cells solder layer. Solar Energy Materials and Solar Cells, 2014, 130, 397-400.	6.2	21
66	Microstructures and fatigue life of SnAgCu solder joints bearing Nano-Al particles in QFP devices. Electronic Materials Letters, 2014, 10, 645-647.	2.2	19
67	Intermetallic compound layer growth between SnAgCu solder and Cu substrate in electronic packaging. Journal of Materials Science: Materials in Electronics, 2013, 24, 3249-3254.	2.2	31
68	Reliability behavior of lead-free solder joints in electronic components. Journal of Materials Science: Materials in Electronics, 2013, 24, 172-190.	2.2	65
69	Microstructures and Properties of SnZn Lead-Free Solder Joints Bearing La for Electronic Packaging. IEEE Transactions on Electron Devices, 2012, 59, 3269-3272.	3.0	19
70	Effect of Zn on properties and microstructure of SnAgCu alloy. Journal of Materials Science: Materials in Electronics, 2012, 23, 1950-1956.	2.2	34
71	Interface reaction between SnAgCu/SnAgCuCe solders and Cu substrate subjected to thermal cycling and isothermal aging. Journal of Alloys and Compounds, 2012, 510, 38-45.	5.5	106
72	Development of SnAg-based lead free solders in electronics packaging. Microelectronics Reliability, 2012, 52, 559-578.	1.7	94

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73	Effect Mechanism of Rare Earth on the Microstructures of SnAgCu Solder Joints. Jixie Gongcheng Xuebao/Chinese Journal of Mechanical Engineering, 2012, 48, 55.	0.5	2
74	Interfacial microstructure and properties of Sn ^{0.7} Cu ^{0.05} Ni/Cu solder joint with rare earth Nd addition. Journal of Alloys and Compounds, 2011, 509, 7152-7161.	5.5	28
75	Properties and microstructure of Sn ^{0.7} Cu ^{0.05} Ni solder bearing rare earth element Pr. Journal of Materials Science: Materials in Electronics, 2011, 22, 1101-1108.	2.2	18
76	Recent advances on Sn ^{0.7} Cu solders with alloying elements: review. Journal of Materials Science: Materials in Electronics, 2011, 22, 565-578.	2.2	61
77	Development of Sn ^{0.7} Zn lead-free solders bearing alloying elements. Journal of Materials Science: Materials in Electronics, 2010, 21, 1-15.	2.2	106
78	Effect of praseodymium on the microstructure and properties of Sn _{3.8} Ag _{0.7} Cu solder. Journal of Materials Science: Materials in Electronics, 2010, 21, 910-916.	2.2	31
79	Properties of SnAgCu/SnAgCuCe soldered joints for electronic packaging. Journal of Materials Science: Materials in Electronics, 2010, 21, 635-642.	2.2	13
80	Effects of trace rare earth Nd addition on microstructure and properties of SnAgCu solder. Journal of Materials Science: Materials in Electronics, 2010, 21, 643-648.	2.2	51
81	A review on the interfacial intermetallic compounds between Sn ^{0.7} Ag ^{0.05} Cu based solders and substrates. Journal of Materials Science: Materials in Electronics, 2010, 21, 421-440.	2.2	140
82	Effects of trace amount addition of rare earth on properties and microstructure of Sn ^{0.7} Ag ^{0.05} Cu alloys. Journal of Materials Science: Materials in Electronics, 2009, 20, 1193-1199.	2.2	42
83	Effects of rare earths on properties and microstructures of lead-free solder alloys. Journal of Materials Science: Materials in Electronics, 2009, 20, 685-694.	2.2	82
84	Effects of cerium on Sn-Ag-Cu alloys based on finite element simulation and experiments. Journal of Rare Earths, 2009, 27, 138-144.	4.8	36